

RELIABILITY REPORT



RELIABILITY DATA
LT1241 / 42 / 43 / 44 / 45 / 46 / 47 / 48 / 49 / LT1950
8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF FAILURES ⁽²⁾
CERDIP	127	9219	0045	499.05	0
SIDEBRAZE	50	9101	9101	42.00	0
PLASTIC DIP	440	9101	0014	1,129.09	0
SOIC/SOT/MSOP	276	9244	0145	537.91	0
	893			2,208.05	0

• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽⁴⁾ AT +85°C	NUMBER OF FAILURES
SOIC/SOT/MSOP	100	9428	9428	48.00	0
	100			48.00	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	4,343	9134	0117	218.24	0
SOIC/SOT/MSOP	5,346	9213	0048	189.74	0
	9,689			407.98	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	1,589	9134	0117	202.17	0
SOIC/SOT/MSOP	1,091	9244	0030	109.10	0
	2,680			311.27	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	920	9151	9906	112.50	0
SOIC/SOT/MSOP	774	9213	0030	77.40	0
	1,694			189.90	0

(1) Assumes Activation Energy = 1.0 Electron Volts
(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 0.83 FITS
(3) Mean Time Between Failures in Years = 137,442
(4) Assumes 20X Acceleration from 85°C to +131°C
Note: 1 FIT = 1 Failure in One Billion Hours.